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US Dept. of Commerce PATENT & TRADEMARK OFFICE

ATTY DOCKET NO. 07447.0043-C APPLICATION NO. 09/456,105

MAY 2 7 2003 INFORMATION DISCLOSURE STATEMENT Assessed sheets if necessary)

David L. Hecht et al. **APPLICANT**

FILING DATE 12/6/1999 **GROUP ART UNIT 2876**

U.S. PATENT DOCUMENTS

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EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE	CLASS	SUB CLASS
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1	5,988,505	11/23/1999	Shellhammer	235	462.09
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FOREIGN PATENT DOCUMENTS

	COUNTRY	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	TRANSLATION Y/N
100	EP	0 469 864	5/5/1992	Xerox Corporation	Y
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OTHER DOCUMENTS (Including Author (in CAPS), Title, Publication Date, Pages, etc.)

EP Search Report for application EP 00 31 0774 (U.S. Counterparts 09/454,526, 09/4	55,304	and
09/456,105) dated April 25, 2003.		

EXAMINER

DATE CONSIDERED \

Examiner: Initial incitation considered, whether or not citation is in conformance with M.P.E.P. 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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ω ω		EP	0 254 644 A2	1/2	27/88	Fairchild Semicon Corporation			Y
		EP	0 923 050 A2	6/1	16/99	Affymetrix, In	C.		Υ
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MC			Report for application) dated July 18, 2003		774 (U.S.	Counterparts 09/454,526	6; 09/455,30	4 and	
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